

IN THE SPECIFICATION:

Please amend the specification by replacing paragraphs [0042] and [0058] as follows:

[0042] In one aspect, during substrate inspection the substrate surface is imaged, i.e., sampled, during the movement of the substrate 28 by the imaging system 150. For example, FIG. 7 illustrates the substrate 28 in position for the imaging system 150 to capture the image 32A at image position A. FIG. [[9]] 8 illustrates the substrate 28 in position for the imaging system 150 to capture an image 32G at image position G. FIG. 9 illustrates the substrate 28 in position for the imaging system 150 to capture the image 32I at image position I.